Notice of References Cited

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Application/Control No.	Applicant(s)/Patent Under	
10/035,556	Reexamination SATAKE, RUMO	
Examiner	Art Unit	
Joseph Nguyen	2815 Page 1 o	f 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,441,877 B1	08-2002	Watanabe, Takahiko	349/138
	В	US-5,978,056	11-1999	Shintani et al.	349/137
•	C	US-			
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Ι	US-			
	_	US-			
	J	US-			
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FOREIGN PATENT DOCUMENTS

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Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | SHIBATA ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

×		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,252,255 B1	06-2001	Ueta et al.	257/94
	В	US-6,593,016 B1	07-2003	Chiyo et al.	428/698
	င	US-6,265,089 B1	07-2001	Fatemi et al.	428/698
	D	US-6,635,904 B2	10-2003	Goetz et al.	257/103
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.